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# Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

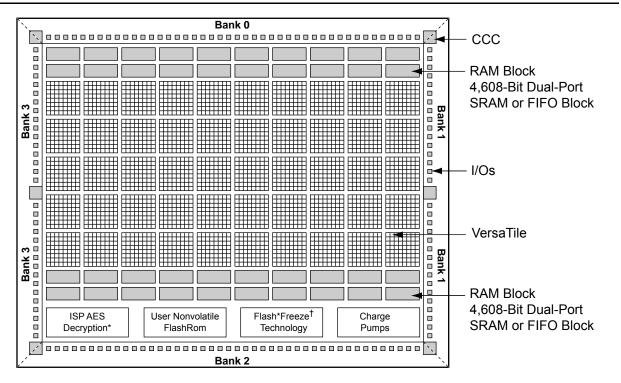
#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	110592
Number of I/O	97
Number of Gates	600000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	144-LBGA
Supplier Device Package	144-FPBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3p600l-fg144i

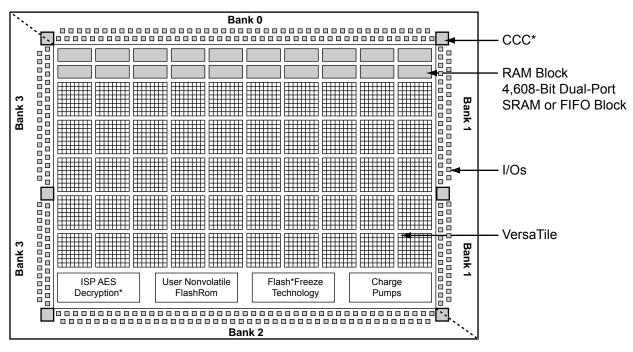
Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Note: Flash\*Freeze technology only applies to IGLOO and ProASIC3L families.

Figure 1-5 • IGLOO, IGLOO nano, ProASIC3 nano, and ProASIC3/L Device Architecture Overview with Four I/O Banks (AGL600 device is shown)



Note: \* AGLP030 does not contain a PLL or support AES security.

Figure 1-6 • IGLOO PLUS Device Architecture Overview with Four I/O Banks

#### Figure 3-18 • Globals Management GUI in Designer

- 3. Occasionally, the synthesis tool assigns a global macro to clock nets, even though the fanout is significantly less than other asynchronous signals. Select **Demote global nets whose fanout is less than** and enter a reasonable value for fanouts. This frees up some global networks from the signals that have very low fanouts. This can also be done using PDC.
- 4. Use a local clock network for the signals that do not need to go to the whole chip but should have low skew. This local clock network assignment can only be done using PDC.
- 5. Assign the I/O buffer using MVN if you have fixed I/O assignment. As shown in Figure 3-10 on page 61, there are three sets of global pins that have a hardwired connection to each global network. Do not try to put multiple CLKBUF macros in these three sets of global pins. For example, do not assign two CLKBUFs to GAA0x and GAA2x pins.
- 6. You must click **Commit** at the end of MVN assignment. This runs the pre-layout checker and checks the validity of global assignment.
- 7. Always run Compile with the **Keep existing physical constraints** option on. This uses the quadrant clock network assignment in the MVN assignment and checks if you have the desired signals on the global networks.
- 8. Run Layout and check the timing.

## Simple Design Example

Consider a design consisting of six building blocks (shift registers) and targeted for an A3PE600-PQ208 (Figure 3-16 on page 68). The example design consists of two PLLs (PLL1 has GLA only; PLL2 has both GLA and GLB), a global reset (ACLR), an enable (EN\_ALL), and three external clock domains (QCLK1, QCLK2, and QCLK3) driving the different blocks of the design. Note that the PQ208 package only has two PLLs (which access the chip global network). Because of fanout, the global reset and enable signals need to be assigned to the chip global resources. There is only one free chip global for the remaining global (QCLK1, QCLK2, QCLK3). Place two of these signals on the quadrant global resource. The design example demonstrates manually assignment of QCLK1 and QCLK2 to the quadrant global using the PDC command.

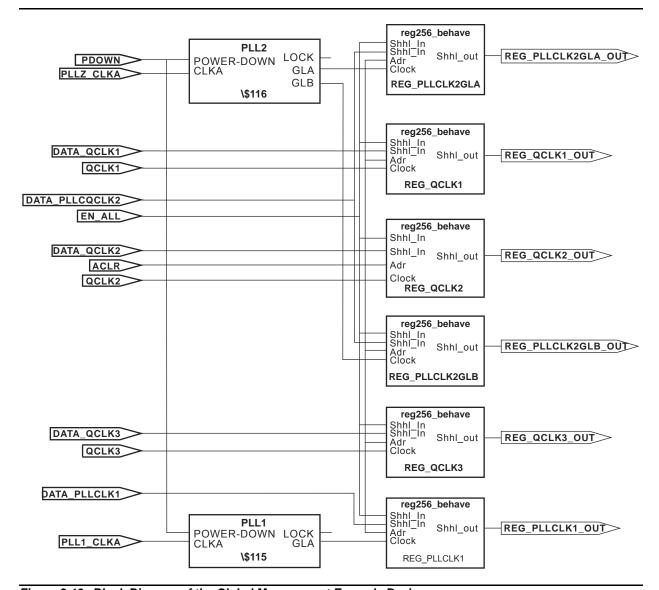


Figure 3-19 • Block Diagram of the Global Management Example Design

Global Resources in Low Power Flash Devices

# **Using Spines of Occupied Global Networks**

When a signal is assigned to a global network, the flash switches are programmed to set the MUX select lines (explained in the "Clock Aggregation Architecture" section on page 61) to drive the spines of that network with the global net. However, if the global net is restricted from reaching into the scope of a spine, the MUX drivers of that spine are available for other high-fanout or critical signals (Figure 3-20).

For example, if you want to limit the CLK1\_c signal to the left half of the chip and want to use the right side of the same global network for CLK2 c, you can add the following PDC commands:

```
define_region -name region1 -type inclusive 0 0 34 29
assign_net_macros region1 CLK1_c
assign_local_clock -net CLK2_c -type chip B2
```

Figure 3-20 • Design Example Using Spines of Occupied Global Networks

# Conclusion

IGLOO, Fusion, and ProASIC3 devices contain 18 global networks: 6 chip global networks and 12 quadrant global networks. These global networks can be segmented into local low-skew networks called spines. The spines provide low-skew networks for the high-fanout signals of a design. These allow you up to 252 different internal/external clocks in an A3PE3000 device. This document describes the architecture for the global network, plus guidelines and methodologies in assigning signals to globals and spines.

# **Related Documents**

### **User's Guides**

IGLOO, ProASIC3, SmartFusion, and Fusion Macro Library Guide http://www.microsemi.com/soc/documents/pa3\_libguide\_ug.pdf

# **List of Changes**

The following table lists critical changes that were made in each revision of the chapter.

Date	Changes	Page
July 2010	This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides.	N/A
	Notes were added where appropriate to point out that IGLOO nano and ProASIC3 nano devices do not support differential inputs (SAR 21449).	N/A
	The "Global Architecture" section and "VersaNet Global Network Distribution" section were revised for clarity (SARs 20646, 24779).	47, 49
	The "I/O Banks and Global I/Os" section was moved earlier in the document, renamed to "Chip and Quadrant Global I/Os", and revised for clarity. Figure 3-4 • Global Connections Details, Figure 3-6 • Global Inputs, Table 3-2 • Chip Global Pin Name, and Table 3-3 • Quadrant Global Pin Name are new (SARs 20646, 24779).	51
	The "Clock Aggregation Architecture" section was revised (SARs 20646, 24779).	57
	Figure 3-7 • Chip Global Aggregation was revised (SARs 20646, 24779).	59
	The "Global Macro and Placement Selections" section is new (SARs 20646, 24779).	64
v1.4 (December 2008)	The "Global Architecture" section was updated to include 10 k devices, and to include information about VersaNet global support for IGLOO nano devices.	47
	The Table 3-1 • Flash-Based FPGAs was updated to include IGLOO nano and ProASIC3 nano devices.	48
	The "VersaNet Global Network Distribution" section was updated to include 10 k devices and to note an exception in global lines for nano devices.	49
	Figure 3-2 • Simplified VersaNet Global Network (30 k gates and below) is new.	50
	The "Spine Architecture" section was updated to clarify support for 10 k and nano devices.	57
	Table 3-4 • Globals/Spines/Rows for IGLOO and ProASIC3 Devices was updated to include IGLOO nano and ProASIC3 nano devices.	57
	The figure in the CLKBUF_LVDS/LVPECL row of Table 3-8 • Clock Macros was updated to change CLKBIBUF to CLKBUF.	62
v1.3 (October 2008)	A third bullet was added to the beginning of the "Global Architecture" section: In Fusion devices, the west CCC also contains a PLL core. In the two larger devices (AFS600 and AFS1500), the west and east CCCs each contain a PLL.	47
	The "Global Resource Support in Flash-Based Devices" section was revised to include new families and make the information more concise.	48
	Table 3-4 • Globals/Spines/Rows for IGLOO and ProASIC3 Devices was updated to include A3PE600/L in the device column.	57
	Table note 1 was revised in Table 3-9 • I/O Standards within CLKBUF to include AFS600 and AFS1500.	63
v1.2 (June 2008)	The following changes were made to the family descriptions in Table 3-1 • Flash-Based FPGAs:  • ProASIC3L was updated to include 1.5 V.	48
	The number of PLLs for ProASIC3E was changed from five to six.	

# 4 - Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs

# Introduction

This document outlines the following device information: Clock Conditioning Circuit (CCC) features, PLL core specifications, functional descriptions, software configuration information, detailed usage information, recommended board-level considerations, and other considerations concerning clock conditioning circuits and global networks in low power flash devices or mixed signal FPGAs.

# **Overview of Clock Conditioning Circuitry**

In Fusion, IGLOO, and ProASIC3 devices, the CCCs are used to implement frequency division, frequency multiplication, phase shifting, and delay operations. The CCCs are available in six chip locations—each of the four chip corners and the middle of the east and west chip sides. For device-specific variations, refer to the "Device-Specific Layout" section on page 94.

The CCC is composed of the following:

- · PLL core
- · 3 phase selectors
- · 6 programmable delays and 1 fixed delay that advances/delays phase
- 5 programmable frequency dividers that provide frequency multiplication/division (not shown in Figure 4-6 on page 87 because they are automatically configured based on the user's required frequencies)
- · 1 dynamic shift register that provides CCC dynamic reconfiguration capability

Figure 4-1 provides a simplified block diagram of the physical implementation of the building blocks in each of the CCCs.

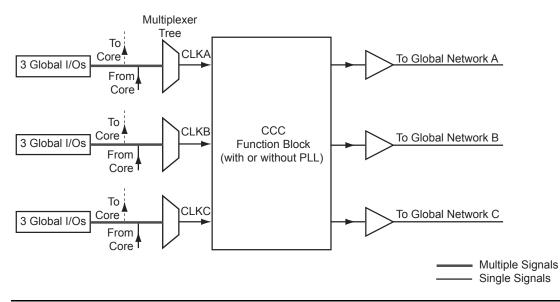


Figure 4-1 • Overview of the CCCs Offered in Fusion, IGLOO, and ProASIC3

Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs

# **Global Buffers with No Programmable Delays**

Access to the global / quadrant global networks can be configured directly from the global I/O buffer, bypassing the CCC functional block (as indicated by the dotted lines in Figure 4-1 on page 77). Internal signals driven by the FPGA core can use the global / quadrant global networks by connecting via the routed clock input of the multiplexer tree.

There are many specific CLKBUF macros supporting the wide variety of single-ended I/O inputs (CLKBUF) and differential I/O standards (CLKBUF\_LVDS/LVPECL) in the low power flash families. They are used when connecting global I/Os directly to the global/quadrant networks.

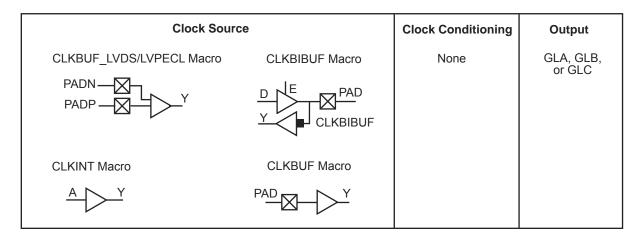
Note: IGLOO nano and ProASIC nano devices do not support differential inputs.

When an internal signal needs to be connected to the global/quadrant network, the CLKINT macro is used to connect the signal to the routed clock input of the network's MUX tree.

To utilize direct connection from global I/Os or from internal signals to the global/quadrant networks, CLKBUF, CLKBUF LVPECL/LVDS, and CLKINT macros are used (Figure 4-2).

- The CLKBUF and CLKBUF\_LVPECL/LVDS<sup>1</sup> macros are composite macros that include an I/O macro driving a global buffer, which uses a hardwired connection.
- The CLKBUF, CLKBUF\_LVPECL/LVDS<sup>1</sup> and CLKINT macros are pass-through clock sources and do not use the PLL or provide any programmable delay functionality.
- The CLKINT macro provides a global buffer function driven internally by the FPGA core.

The available CLKBUF macros are described in the *IGLOO*, *ProASIC3*, *SmartFusion*, and *Fusion Macro Library Guide*.



Note: IGLOO nano and ProASIC nano devices do not support differential inputs.

Figure 4-2 • CCC Options: Global Buffers with No Programmable Delay

# **Global Buffer with Programmable Delay**

Clocks requiring clock adjustments can utilize the programmable delay cores before connecting to the global / quadrant global networks. A maximum of 18 CCC global buffers can be instantiated in a device—three per CCC and up to six CCCs per device.

Each CCC functional block contains a programmable delay element for each of the global networks (up to three), and users can utilize these features by using the corresponding macro (Figure 4-3 on page 81).

<sup>1.</sup> B-LVDS and M-LVDS are supported with the LVDS macro.



This section outlines the following device information: CCC features, PLL core specifications, functional descriptions, software configuration information, detailed usage information, recommended board-level considerations, and other considerations concerning global networks in low power flash devices.

## Clock Conditioning Circuits with Integrated PLLs

Each of the CCCs with integrated PLLs includes the following:

- 1 PLL core, which consists of a phase detector, a low-pass filter, and a four-phase voltagecontrolled oscillator
- 3 global multiplexer blocks that steer signals from the global pads and the PLL core onto the global networks
- · 6 programmable delays and 1 fixed delay for time advance/delay adjustments
- 5 programmable frequency divider blocks to provide frequency synthesis (automatically configured by the SmartGen macro builder tool)

# **Clock Conditioning Circuits without Integrated PLLs**

There are two types of simplified CCCs without integrated PLLs in low power flash devices.

- 1. The simplified CCC with programmable delays, which is composed of the following:
  - 3 global multiplexer blocks that steer signals from the global pads and the programmable delay elements onto the global networks
  - 3 programmable delay elements to provide time delay adjustments
- 2. The simplified CCC (referred to as CCC-GL) without programmable delay elements, which is composed of the following:
  - A global multiplexer block that steer signals from the global pads onto the global networks



Table 4-9 to Table 4-15 on page 110 provide descriptions of the configuration data for the configuration bits.

### Table 4-9 • Input Clock Divider, FINDIV[6:0] (/n)

FINDIV<6:0> State	Divisor	New Frequency Factor
0	1	1.00000
1	2	0.50000
:	:	:
127	128	0.0078125

### Table 4-10 • Feedback Clock Divider, FBDIV[6:0] (/m)

FBDIV<6:0> State	Divisor	New Frequency Factor
0	1	1
1	2	2
:	:	i i
127	128	128

### Table 4-11 • Output Frequency Dividers

A Output Divider, OADIV <4:0> (/u);

B Output Divider, OBDIV <4:0> (/v);

C Output Divider, OCDIV <4:0> (/w)

OADIV<4:0>; OBDIV<4:0>; CDIV<4:0> State	Divisor	New Frequency Factor
0	1	1.00000
1	2	0.50000
:	:	i i
31	32	0.03125

### Table 4-12 • MUXA, MUXB, MUXC

OAMUX<2:0>; OBMUX<2:0>; OCMUX<2:0> State	MUX Input Selected
0	None. Six-input MUX and PLL are bypassed. Clock passes only through global MUX and goes directly into HC ribs.
1	Not available
2	PLL feedback delay line output
3	Not used
4	PLL VCO 0° phase shift
5	PLL VCO 270° phase shift
6	PLL VCO 180° phase shift
7	PLL VCO 90° phase shift

ProASIC3L FPGA Fabric User's Guide

256×18 FIFO is full, even though a 128×18 FIFO was requested. For this example, the Almost-Full flag can be used instead of the Full flag to signal when the 128th data word is reached.

To accommodate different aspect ratios, the almost-full and almost-empty values are expressed in terms of data bits instead of data words. SmartGen translates the user's input, expressed in data words, into data bits internally. SmartGen allows the user to select the thresholds for the Almost-Empty and Almost-Full flags in terms of either the read data words or the write data words, and makes the appropriate conversions for each flag.

After the empty or full states are reached, the FIFO can be configured so the FIFO counters either stop or continue counting. For timing numbers, refer to the appropriate family datasheet.

### Signal Descriptions for FIFO4K18

The following signals are used to configure the FIFO4K18 memory element:

#### WW and RW

These signals enable the FIFO to be configured in one of the five allowable aspect ratios (Table 6-6).

Table 6-6 • Aspect Ratio Settings for WW[2:0]

WW[2:0]	RW[2:0]	D×W
000	000	4k×1
001	001	2k×2
010	010	1k×4
011	011	512×9
100	100	256×18
101, 110, 111	101, 110, 111	Reserved

#### **WBLK and RBLK**

These signals are active-low and will enable the respective ports when LOW. When the RBLK signal is HIGH, that port's outputs hold the previous value.

#### **WEN and REN**

Read and write enables. WEN is active-low and REN is active-high by default. These signals can be configured as active-high or -low.

#### **WCLK and RCLK**

These are the clock signals for the synchronous read and write operations. These can be driven independently or with the same driver.

Note: For the Automotive ProASIC3 FIFO4K18, for the same clock, 180° out of phase (inverted) between clock pins should be used.

#### RPIPE

This signal is used to specify pipelined read on the output. A LOW on RPIPE indicates a nonpipelined read, and the data appears on the output in the same clock cycle. A HIGH indicates a pipelined read, and data appears on the output in the next clock cycle.

#### RESET

This active-low signal resets the control logic and forces the output hold state registers to zero when asserted. It does not reset the contents of the memory array (Table 6-7 on page 160).

While the RESET signal is active, read and write operations are disabled. As with any asynchronous RESET signal, care must be taken not to assert it too close to the edges of active read and write clocks.

#### WD

This is the input data bus and is 18 bits wide. Not all 18 bits are valid in all configurations. When a data width less than 18 is specified, unused higher-order signals must be grounded (Table 6-7 on page 160).

# Conclusion

Fusion, IGLOO, and ProASIC3 devices provide users with extremely flexible SRAM blocks for most design needs, with the ability to choose between an easy-to-use dual-port memory or a wide-word two-port memory. Used with the built-in FIFO controllers, these memory blocks also serve as highly efficient FIFOs that do not consume user gates when implemented. The SmartGen core generator provides a fast and easy way to configure these memory elements for use in designs.

# **List of Changes**

The following table lists critical changes that were made in each revision of the chapter.

Date	Changes	Page
August 2012	The note connected with Figure 6-3 • Supported Basic RAM Macros, regarding RAM4K9, was revised to explain that it applies only to part numbers of certain revisions and earlier (SAR 29574).	152
July 2010	This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides.	N/A
v1.5 (December 2008)	IGLOO nano and ProASIC3 nano devices were added to Table 6-1 • Flash-Based FPGAs.	150
	IGLOO nano and ProASIC3 nano devices were added to Figure 6-8 • Interfacing TAP Ports and SRAM Blocks.	164
v1.4 (October 2008)	The "SRAM/FIFO Support in Flash-Based Devices" section was revised to include new families and make the information more concise.	150
	The "SRAM and FIFO Architecture" section was modified to remove "IGLOO and ProASIC3E" from the description of what the memory block includes, as this statement applies to all memory blocks.	151
	Wording in the "Clocking" section was revised to change "IGLOO and ProASIC3 devices support inversion" to "Low power flash devices support inversion." The reference to IGLOO and ProASIC3 development tools in the last paragraph of the section was changed to refer to development tools in general.	157
	The "ESTOP and FSTOP Usage" section was updated to refer to FIFO counters in devices in general rather than only IGLOO and ProASIC3E devices.	160
v1.3 (August 2008)	The note was removed from Figure 6-7 • RAM Block with Embedded FIFO Controller and placed in the WCLK and RCLK description.	158
	The "WCLK and RCLK" description was revised.	159
v1.2 (June 2008)	The following changes were made to the family descriptions in Table 6-1 • Flash-Based FPGAs:	150
	ProASIC3L was updated to include 1.5 V.	
	The number of PLLs for ProASIC3E was changed from five to six.	
v1.1 (March 2008)	The "Introduction" section was updated to include the IGLOO PLUS family.	147
	The "Device Architecture" section was updated to state that 15 k gate devices do not support SRAM and FIFO.	147
	The first note in Figure 6-1 • IGLOO and ProASIC3 Device Architecture Overview was updated to include mention of 15 k gate devices, and IGLOO PLUS was added to the second note.	149

I/O Structures in IGLOO and ProASIC3 Devices

# I/O Standards

## Single-Ended Standards

These I/O standards use a push-pull CMOS output stage with a voltage referenced to system ground to designate logical states. The input buffer configuration, output drive, and I/O supply voltage (VCCI) vary among the I/O standards (Figure 7-5).

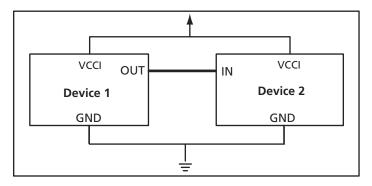


Figure 7-5 • Single-Ended I/O Standard Topology

The advantage of these standards is that a common ground can be used for multiple I/Os. This simplifies board layout and reduces system cost. Their low-edge-rate (*dv/dt*) data transmission causes less electromagnetic interference (EMI) on the board. However, they are not suitable for high-frequency (>200 MHz) switching due to noise impact and higher power consumption.

### LVTTL (Low-Voltage TTL)

This is a general-purpose standard (EIA/JESD8-B) for 3.3 V applications. It uses an LVTTL input buffer and a push-pull output buffer. The LVTTL output buffer can have up to six different programmable drive strengths. The default drive strength is 12 mA. VCCI is 3.3 V. Refer to "I/O Programmable Features" on page 188 for details.

### LVCMOS (Low-Voltage CMOS)

The low power flash devices provide four different kinds of LVCMOS: LVCMOS 3.3 V, LVCMOS 2.5 V, LVCMOS 1.8 V, and LVCMOS 1.5 V. LVCMOS 3.3 V is an extension of the LVCMOS standard (JESD8-B-compliant) used for general-purpose 3.3 V applications.

LVCMOS 2.5 V is an extension of the LVCMOS standard (JESD8-5–compliant) used for general-purpose 2.5 V applications.

There is yet another standard supported by IGLOO and ProASIC3 devices (except A3P030): LVCMOS 2.5/5.0 V. This standard is similar to LVCMOS 2.5 V, with the exception that it can support up to 3.3 V on the input side (2.5 V output drive).

LVCMOS 1.8 V is an extension of the LVCMOS standard (JESD8-7–compliant) used for general-purpose 1.8 V applications. LVCMOS 1.5 V is an extension of the LVCMOS standard (JESD8-11–compliant) used for general-purpose 1.5 V applications.

The VCCI values for these standards are 3.3 V, 2.5 V, 1.8 V, and 1.5 V, respectively. Like LVTTL, the output buffer has up to seven different programmable drive strengths (2, 4, 6, 8, 12, 16, and 24 mA). Refer to "I/O Programmable Features" on page 188 for details.

#### 3.3 V PCI (Peripheral Component Interface)

This standard specifies support for both 33 MHz and 66 MHz PCI bus applications. It uses an LVTTL input buffer and a push-pull output buffer. With the aid of an external resistor, this I/O standard can be 5 V–compliant for low power flash devices. It does not have programmable drive strength.

# 3.3 V PCI-X (Peripheral Component Interface Extended)

An enhanced version of the PCI specification, 3.3 V PCI-X can support higher average bandwidths; it increases the speed that data can move within a computer from 66 MHz to 133 MHz. It is backward-

# 9 – I/O Software Control in Low Power Flash Devices

Fusion, IGLOO, and ProASIC3 I/Os provide more design flexibility, allowing the user to control specific features by enabling certain I/O standards. Some features are selectable only for certain I/O standards, whereas others are available for all I/O standards. For example, slew control is not supported by differential I/O standards. Conversely, I/O register combining is supported by all I/O standards. For detailed information about which I/O standards and features are available on each device and each I/O type, refer to the I/O Structures section of the handbook for the device you are using.

Figure 9-1 shows the various points in the software design flow where a user can provide input or control of the I/O selection and parameters. A detailed description is provided throughout this document.

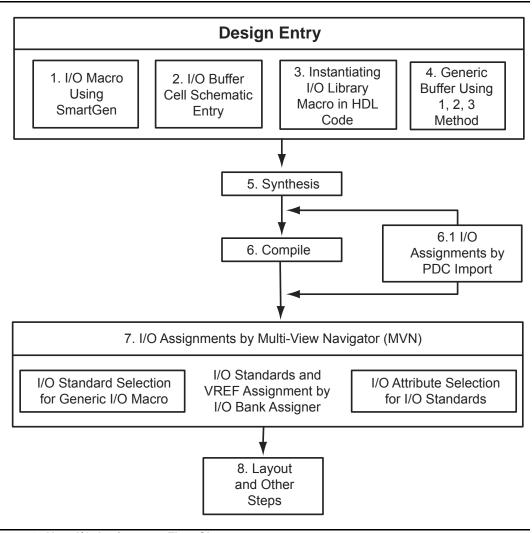


Figure 9-1 • User I/O Assignment Flow Chart

DDR for Microsemi's Low Power Flash Devices

# **Design Example**

Figure 10-9 shows a simple example of a design using both DDR input and DDR output registers. The user can copy the HDL code in Libero SoC software and go through the design flow. Figure 10-10 and Figure 10-11 on page 283 show the netlist and ChipPlanner views of the ddr\_test design. Diagrams may vary slightly for different families.

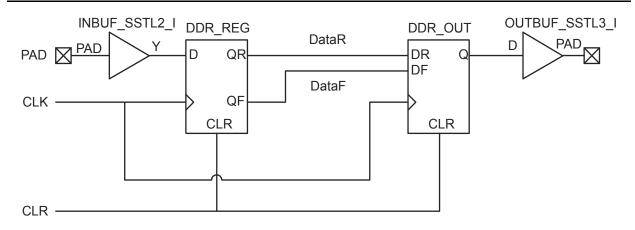


Figure 10-9 • Design Example

Figure 10-10 • DDR Test Design as Seen by NetlistViewer for IGLOO/e Devices



# **List of Changes**

The following table lists critical changes that were made in each revision of the chapter.

Date	Changes	Page
July 2010	FlashPro4 is a replacement for FlashPro3 and has been added to this chapter. FlashPro is no longer available.	N/A
	The chapter was updated to include SmartFusion devices.	N/A
	The following were deleted:	N/A
	"Live at Power-Up (LAPU) or Boot PROM" section	
	"Design Security" section	
	Table 14-2 • Programming Features for Actel Devices and much of the text in the "Programming Features for Microsemi Devices" section	
	"Programming Flash FPGAs" section	
	"Return Material Authorization (RMA) Policies" section	
	The "Device Programmers" section was revised.	291
	The Independent Programming Centers information was removed from the "Volume Programming Services" section.	292
	Table 11-3 • Programming Solutions was revised to add FlashPro4 and note that FlashPro is discontinued. A note was added for FlashPro Lite regarding power supply requirements.	293
	Most items were removed from Table 11-4 • Programming Ordering Codes, including FlashPro3 and FlashPro.	294
	The "Programmer Device Support" section was deleted and replaced with a reference to the Microsemi SoC Products Group website for the latest information.	294
	The "Certified Programming Solutions" section was revised to add FlashPro4 and remove Silicon Sculptor I and Silicon Sculptor 6X. Reference to <i>Programming and Functional Failure Guidelines</i> was added.	294
	The file type *.pdb was added to the "Use the Latest Version of the Designer Software to Generate Your Programming File (recommended)" section.	295
	Instructions on cleaning and careful insertion were added to the "Perform Routine Hardware Self-Diagnostic Test" section. Information was added regarding testing Silicon Sculptor programmers with an adapter module installed before every programming session verifying their calibration annually.	295
	The "Signal Integrity While Using ISP" section is new.	296
	The "Programming Failure Allowances" section was revised.	296



2. Choose the appropriate security level setting and enter a FlashLock Pass Key. The default is the **Medium** security level (Figure 12-12). Click **Next**.

If you want to select different options for the FPGA and/or FlashROM, this can be set by clicking **Custom Level**. Refer to the "Advanced Options" section on page 322 for different custom security level options and descriptions of each.

Figure 12-12 • Medium Security Level Selected for Low Power Flash Devices

In-System Programming (ISP) of Microsemi's Low Power Flash Devices Using FlashPro4/3/3X

- 3. A single STAPL file or multiple STAPL files with multiple FlashROM contents. A single STAPL file will be generated if the device serialization feature is not used. You can program the whole FlashROM or selectively program individual pages.
- A single STAPL file to configure the security settings for the device, such as the AES Key and/or Pass Key.

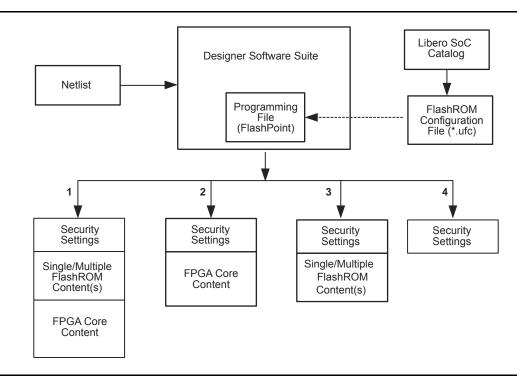


Figure 13-4 • Flexible Programming File Generation for Different Applications

# **Programming Solution**

For device programming, any IEEE 1532–compliant programmer can be used; however, the FlashPro4/3/3X programmer must be used to control the low power flash device's rich security features and FlashROM programming options. The FlashPro4/3/3X programmer is a low-cost portable programmer for the Microsemi flash families. It can also be used with a powered USB hub for parallel programming. General specifications for the FlashPro4/3/3X programmer are as follows:

- Programming clock TCK is used with a maximum frequency of 20 MHz, and the default frequency is 4 MHz.
- Programming file STAPL
- Daisy chain Supported. You can use the ChainBuilder software to build the programming file for the chain.
- Parallel programming Supported. Multiple FlashPro4/3/3X programmers can be connected together using a powered USB hub or through the multiple USB ports on the PC.
- Power supply The target board must provide VCC, VCCI, VPUMP, and VJTAG during programming. However, if there is only one device on the target board, the FlashPro4/3/3X programmer can generate the required VPUMP voltage from the USB port.

# **List of Changes**

The following table lists critical changes that were made in each revision of the chapter.

Date	Changes	Page
August 2012	This chapter will now be published standalone as an application note in addition to being part of the IGLOO/ProASIC3/Fusion FPGA fabric user's guides (SAR 38769).	N/A
	The "ISP Programming Header Information" section was revised to update the description of FP3-10PIN-ADAPTER-KIT in Table 13-3 • Programming Header Ordering Codes, clarifying that it is the adapter kit used for ProASICPLUS based boards, and also for ProASIC3 based boards where a compact programming header is being used (SAR 36779).	335
June 2011	The VPUMP programming mode voltage was corrected in Table 13-2 • Power Supplies. The correct value is 3.15 V to 3.45 V (SAR 30668).	329
	The notes associated with Figure 13-5 • Programming Header (top view) and Figure 13-6 • Board Layout and Programming Header Top View were revised to make clear the fact that IGLOO nano V2 devices can be programmed at 1.2 V (SAR 30787).	335, 337
	Figure 13-6 • Board Layout and Programming Header Top View was revised to include resistors tying TCK and TRST to GND. Microsemi recommends tying off TCK and TRST to GND if JTAG is not used (SAR 22921). RT ProASIC3 was added to the list of device families.	337
	In the "ISP Programming Header Information" section, the kit for adapting ProASICPLUS devices was changed from FP3-10PIN-ADAPTER-KIT to FP3-26PIN-ADAPTER-KIT (SAR 20878).	335
July 2010	This chapter is no longer published separately with its own part number and version but is now part of several FPGA fabric user's guides.	N/A
	References to FlashPro4 and FlashPro3X were added to this chapter, giving distinctions between them. References to SmartGen were deleted and replaced with Libero IDE Catalog.	N/A
	The "ISP Architecture" section was revised to indicate that V2 devices can be programmed at 1.2 V VCC with FlashPro4.	327
	SmartFusion was added to Table 13-1 • Flash-Based FPGAs Supporting ISP.	328
	The "Programming Voltage (VPUMP) and VJTAG" section was revised and 1.2 V was added to Table 13-2 • Power Supplies.	329
	The "Nonvolatile Memory (NVM) Programming Voltage" section is new.	329
	Cortex-M3 was added to the "Cortex-M1 and Cortex-M3 Device Security" section.	331
	In the "ISP Programming Header Information" section, the additional header adapter ordering number was changed from FP3-26PIN-ADAPTER to FP3-10PIN-ADAPTER-KIT, which contains 26-pin migration capability.	335
	The description of NC was updated in Figure 13-5 • Programming Header (top view), Table 13-4 • Programming Header Pin Numbers and Description and Figure 13-6 • Board Layout and Programming Header Top View.	335, 336
	The "Symptoms of a Signal Integrity Problem" section was revised to add that customers are expected to troubleshoot board-level signal integrity issues by measuring voltages and taking scope plots. "FlashPro4/3/3X allows TCK to be lowered from 6 MHz down to 1 MHz to allow you to address some signal integrity problems" formerly read, "from 24 MHz down to 1 MHz." "The Scan Chain command expects to see 0x2" was changed to 0x1.	337

Power-Up/-Down Behavior of Low Power Flash Devices

# **Related Documents**

## **Datasheets**

ProASIC3 Flash Family FPGAs
http://www.microsemi.com/soc/documents/PA3\_DS.pdf
ProASIC3E Flash Family FPGAs
http://www.microsemi.com/soc/documents/PA3E\_DS.pdf

# **List of Changes**

The following table lists critical changes that were made in each revision of the chapter.

Date	Changes	Page
v1.2 (December 2008)	IGLOO nano and ProASIC3 nano devices were added to the document as supported device types.	
v1.1 (October 2008)	The "Introduction" section was updated to add Military ProASIC3EL and RT ProASIC3 devices to the list of devices that can have inputs driven in while the device is not powered.	373
	The "Flash Devices Support Power-Up Behavior" section was revised to include new families and make the information more concise.	374
	The "Cold-Sparing" section was revised to add Military ProASIC3/EL and RT ProASIC3 devices to the lists of devices with and without cold-sparing support.	382
	The "Hot-Swapping" section was revised to add Military ProASIC3/EL and RT ProASIC3 devices to the lists of devices with and without hot-swap support. AGL400 was added to the list of devices that do not support hot-swapping.	383
v1.0 (August 2008)	This document was revised, renamed, and assigned a new part number. It now includes data for the IGLOO and ProASIC3L families.	N/A
v1.3 (March 2008)	The "List of Changes" section was updated to include the three different I/O Structure handbook chapters.	384
v1.2 (February 2008)	The first sentence of the "PLL Behavior at Brownout Condition" section was updated to read, "When PLL power supply voltage and/or $V_{CC}$ levels drop below the VCC brownout levels (0.75 V $\pm$ 0.25 V), the PLL output lock signal goes low and/or the output clock is lost."	381
v1.1 (January 2008)	The "PLL Behavior at Brownout Condition" section was added.	381

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